

Course: EE6601 / Advanced Wafer Processing
School: School of Electrical and Electronic Engineering

1- Introduction to Semiconductor Processing



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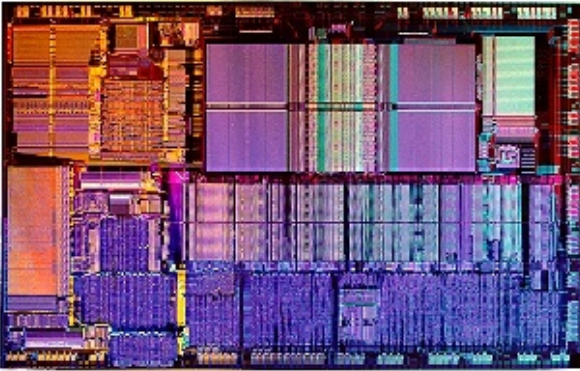
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By the end of this lesson, you should be able to:

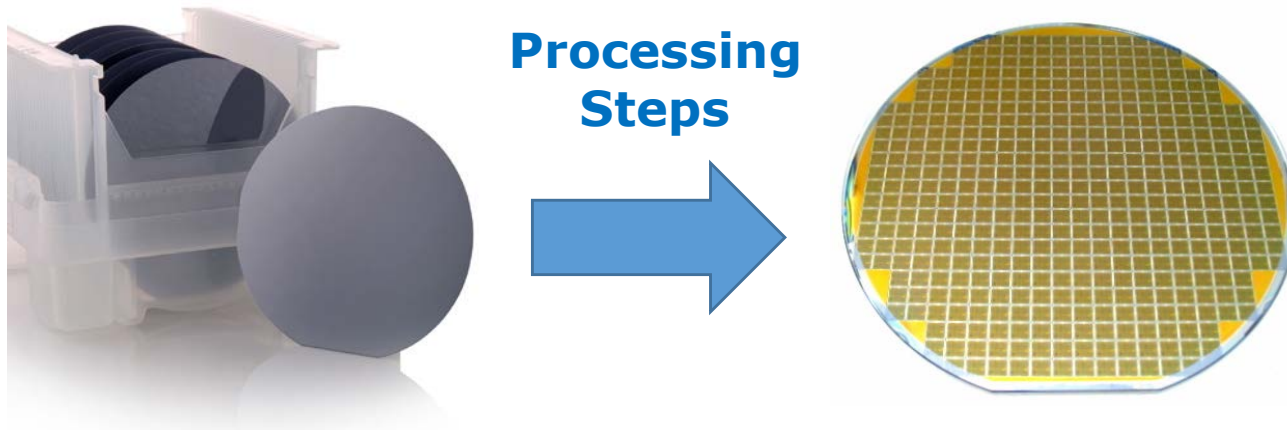
- Explain the processes needed to fabricate semiconductor devices (e.g. MOSFET) from silicon wafers
- Describe the trend of device scaling down over time in the integrated circuit (IC) industry
- Discover the need of a clean room in semiconductor fabrication, and possible contaminants present during fabrication



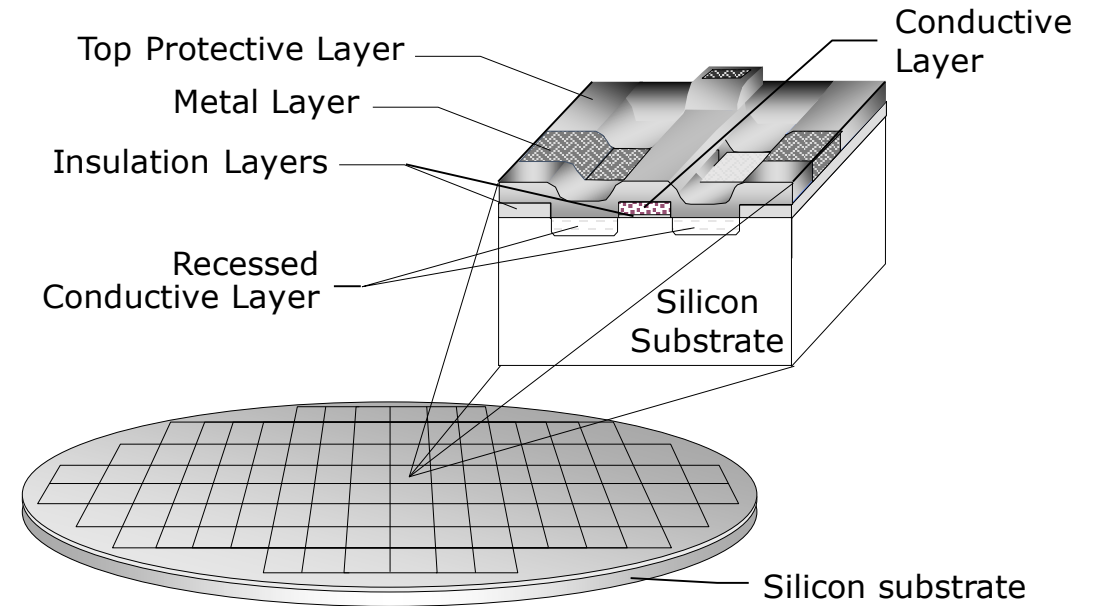
State of art ICs manufactured in the 1990s.

Therefore, you will find this course very useful even though most of you may not work in the IC industry after graduation.

- This course is basically about silicon chip fabrication, the technologies used to manufacture ICs (CPU, memory-DRAM, flash, etc.).
- However, the same technology is also widely used for applications other than ICs, such as large area displays (LCD), hard disk drive, semiconductor lasers, MEMS (Microelectromechanical Systems), lab-on-a-chip, solar cell, etc.
- For nanoapplication, microfabrication is the basis for nanofabrication; with the major difference is that photolithography is used for microfabrication whereas nanolithography (electron beam lithography) is used for nanofabrication.



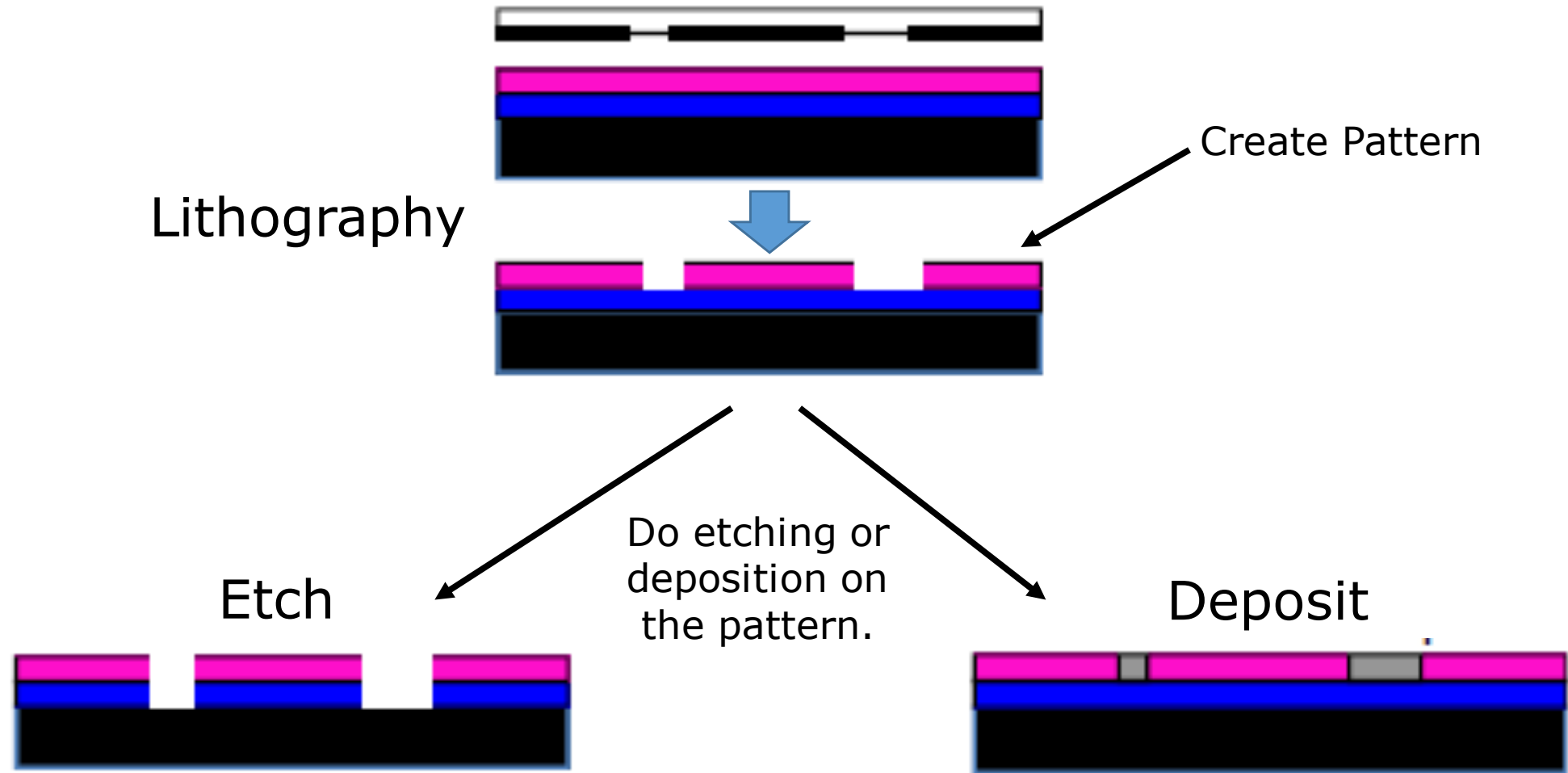
Processing Steps: A sequence of additive and subtractive steps with lateral patterning



Example: MOSFET

Three components for micro- and nanofabrication:

- **Lithography (lateral patterning):** Generate a pattern in a material called resist
 - **Thin film deposition (additive):** Sputtering, evaporation, chemical vapour deposition, etc.
 - **Etching (subtractive):** Wet chemical etching, sputter etching, reactive ion etching, etc.
- Other techniques such as doping (ion implantation) are also important for a semiconductor device.



In the next 10 – 12 lectures, you will learn:

Lithography

Patterning of the substrate
(silicon wafer)

Etching

Removal of materials
on the substrate

Deposition

Deposit materials
(metal or non-metal)
on the substrate

Textbook:

- S.A. Campbell, 'The Science and Engineering of Microelectronics Fabrication', Oxford University Press
- S.A. Campbell, 'Fabrication Engineering at the Micro- and Nanoscale', Oxford University Press

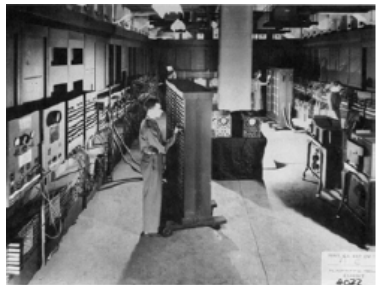
Explosive Growth of Computing Power



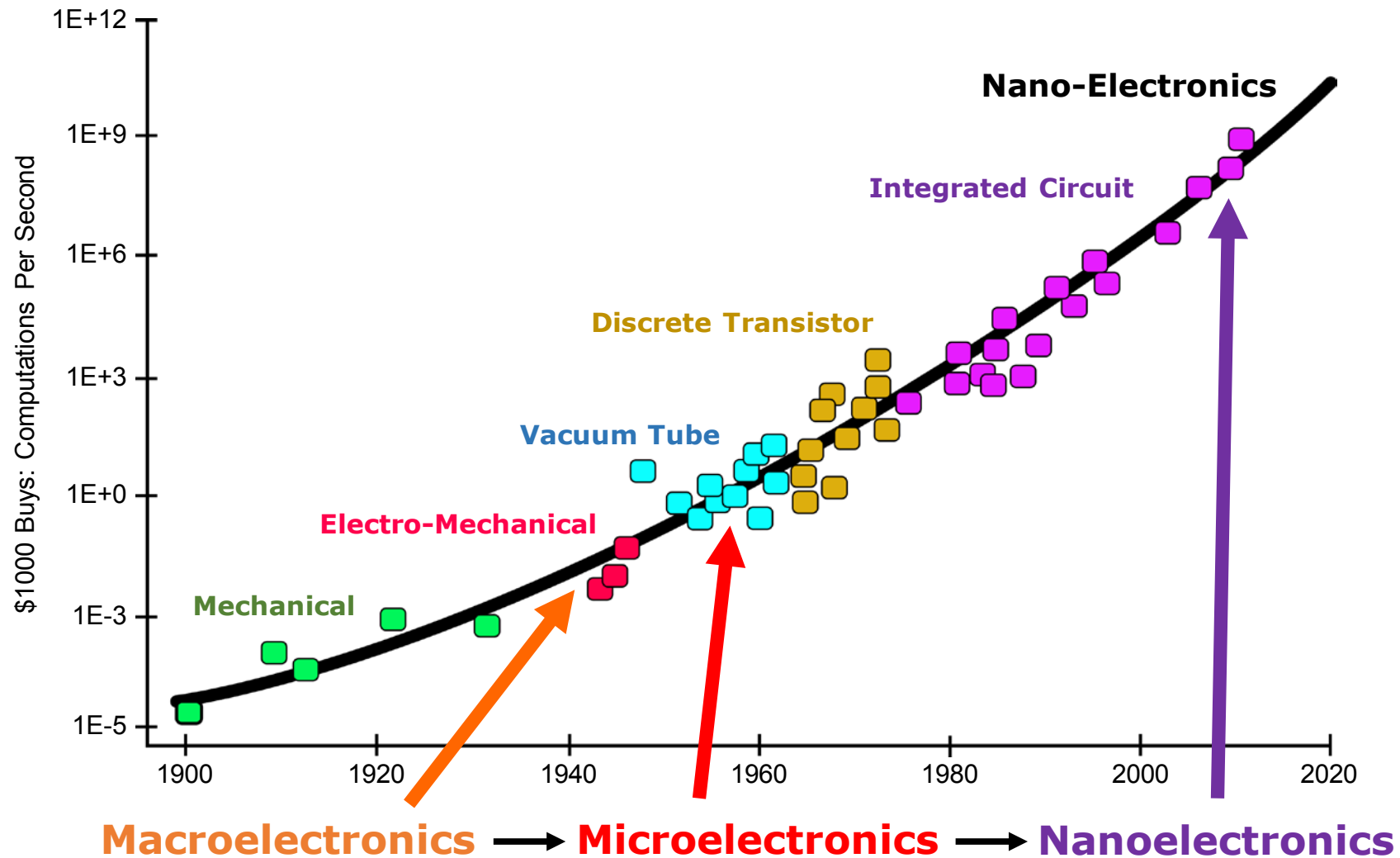
1st Computer (1832)



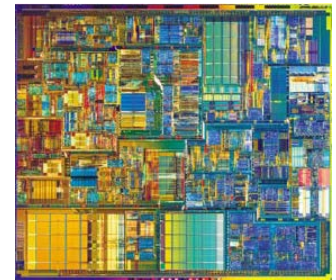
Vacuum Tube



**1st Electronic Computer
ENIAC (1946)**

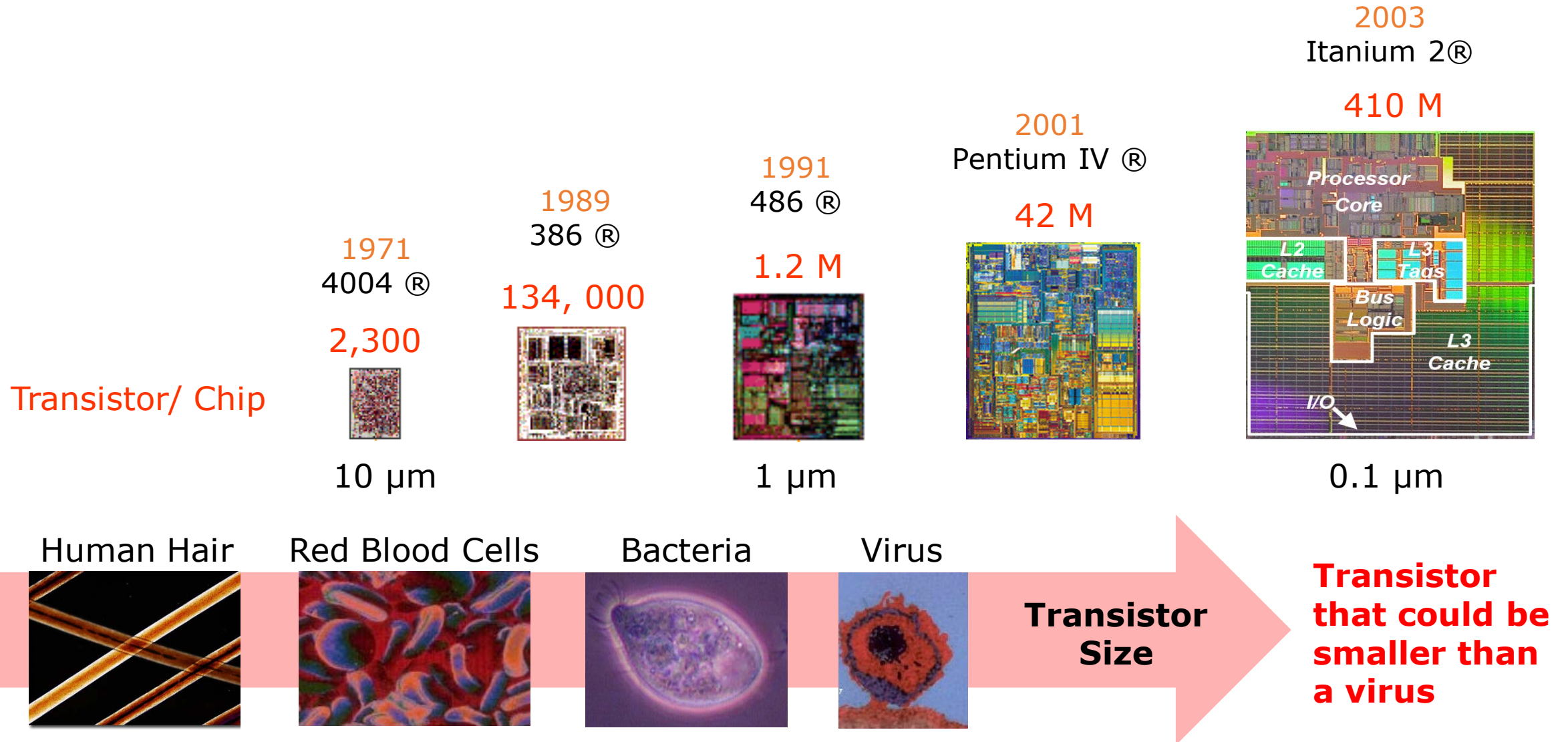


**1st Transistor
(1947)**

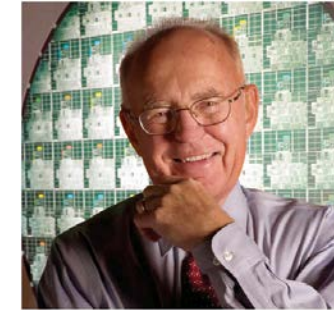
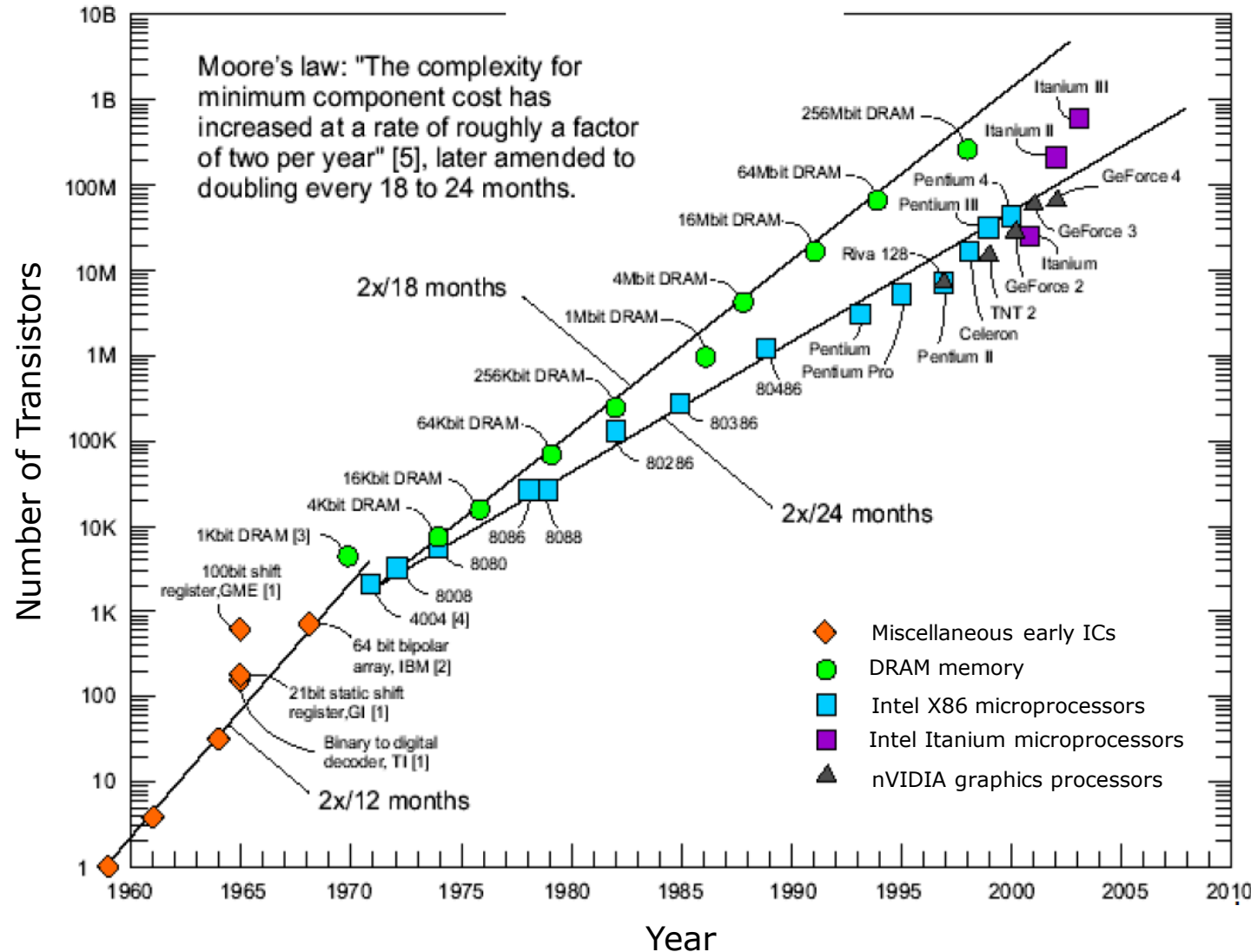


Pentium IV

Explosive Growth of Computing Power



Device Scaling Down Over Time in IC Industry



Gordon Moore:

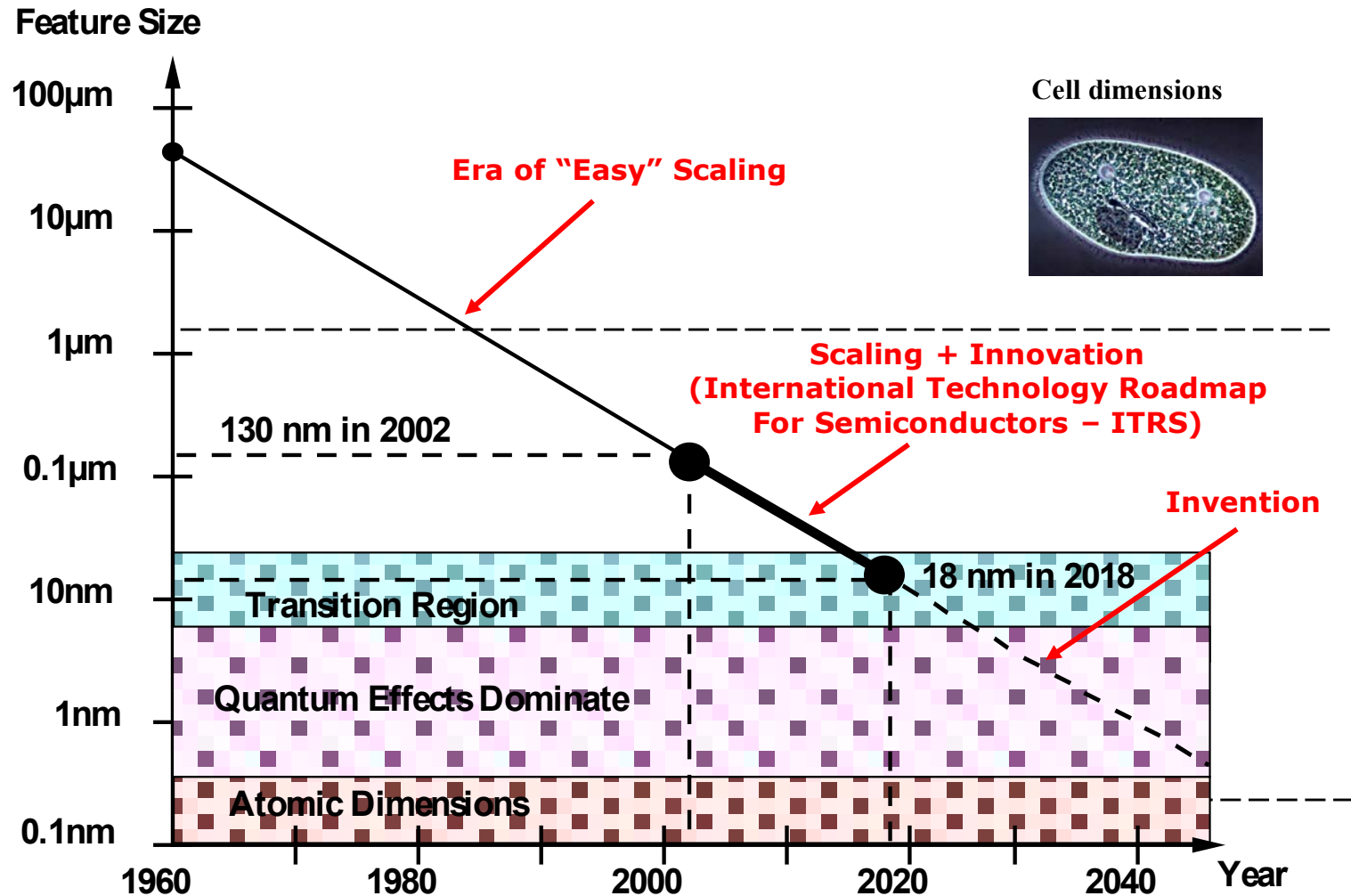
Born 3 January 1929, co-founder and Chairman Emeritus of Intel Corporation; author of Moore's Law published in 1965.

Moore's law: Doubling the number of transistors on a chip roughly every two years.

This is realised by:

- Making transistor smaller – smallest lateral feature size decreases by 13% each year
- Making chip bigger – Chip or wafer size increases 16% per year

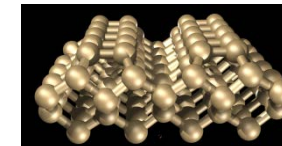
Device Scaling Down Over Time in IC Industry



Cell dimensions



- The era of "easy" scaling is over.
- We are now in a period where technology and device innovations are required.
- Beyond 2020, there will be requirements of unknown inventions.



Atomic dimensions

Device Scaling Down Over Time in IC Industry

- Assumes CMOS technology dominates over entire roadmap
- 2-year cycle moving to 3 years (scaling + innovation required)

SIA-NTRS:		2-year Cycle				3-year Cycle			
Year of Production	1998	2000	2002	2004	2007	2010	2013	2016	2018
Technology Node (Half Pitch)	250 nm	180 nm	130 nm	90 nm	65 nm	45 nm	32 nm	22 nm	18 nm
MPU Printed Gate Length (MPU – Microprocessor Unit)		100 nm	70 nm	53 nm	35 nm	25 nm	18 nm	13 nm	10 nm
DRAM Bits/ Chip (Sampling)	256 M	512 M	1 G	4 G	16 G	32 G	64 G	128 G	128 G
MPU Transistors/ Chip ($\times 10^6$)				550	1,100	2,200	4,400	8,800	14,000
Min Supply Voltage (Volts)	1.8-2.5	1.5-1.8	1.2-1.5	0.9-1.2	0.8-1.1	0.7-1.0	0.6-0.9	0.5-0.8	0.5-0.7

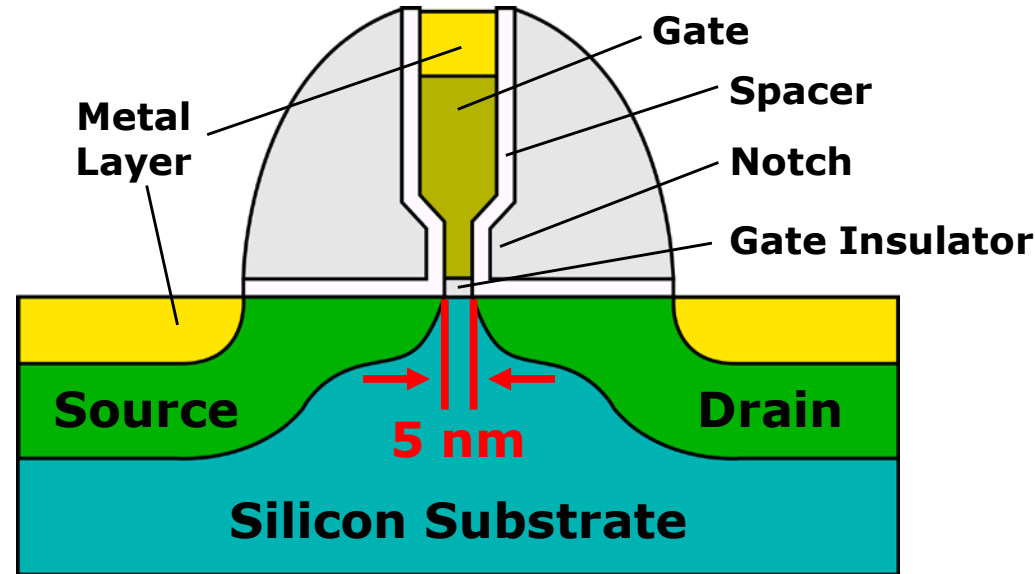
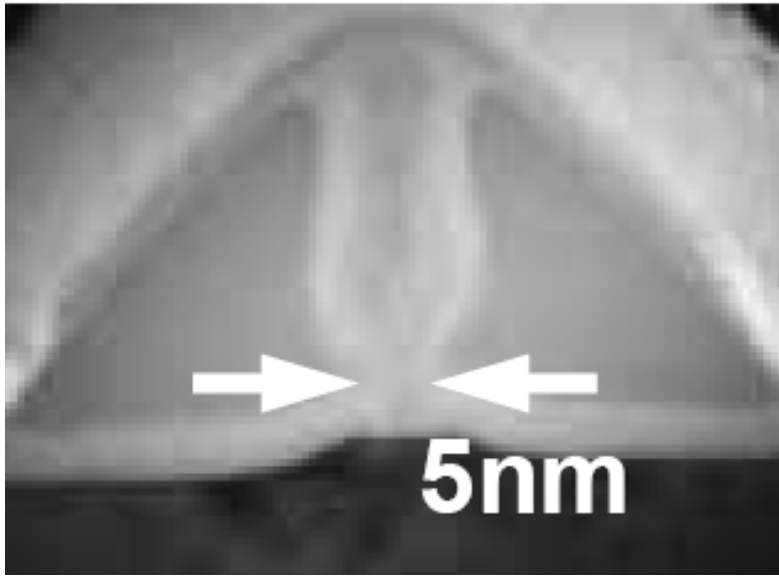
SIA: Semiconductor Industry Association

NTRS: National Technology Roadmap for Semiconductors.

ITRS: International Technology Roadmap for Semiconductors, <http://www.itrs.net>

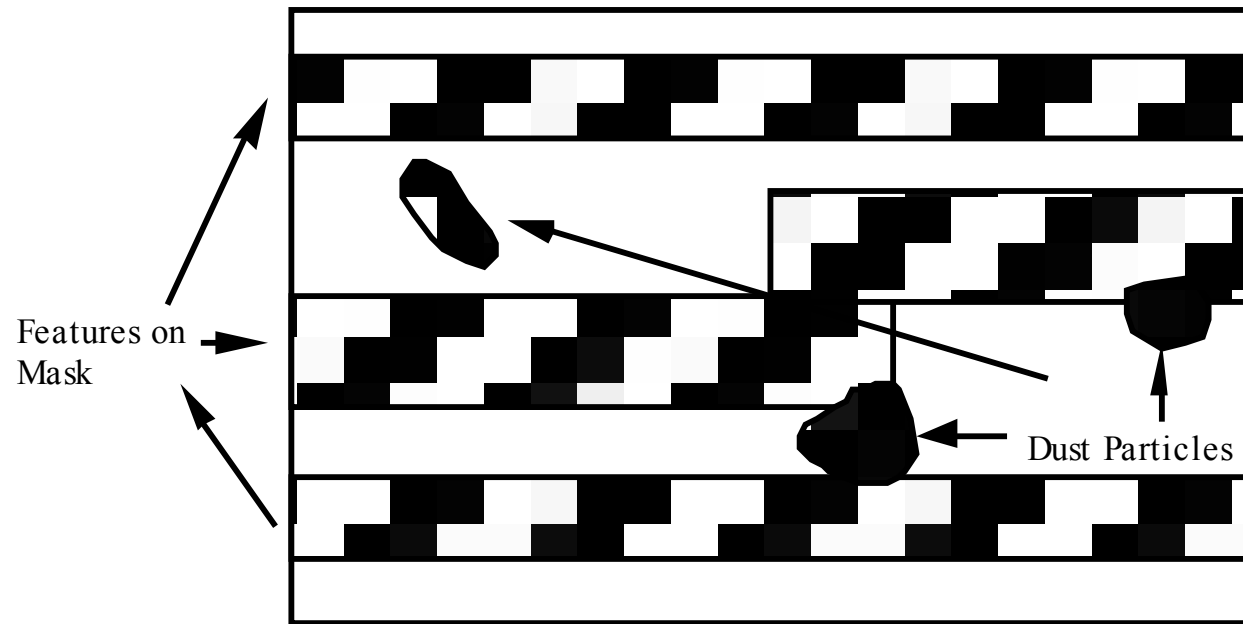
- Scaling down supply voltage because otherwise, as transistors get smaller, the electric fields (voltage/ feature size) in these devices will increase to unacceptable levels

Fabrication of Truly Tiny Transistor



Photograph and figure of 5 nm gate transistor

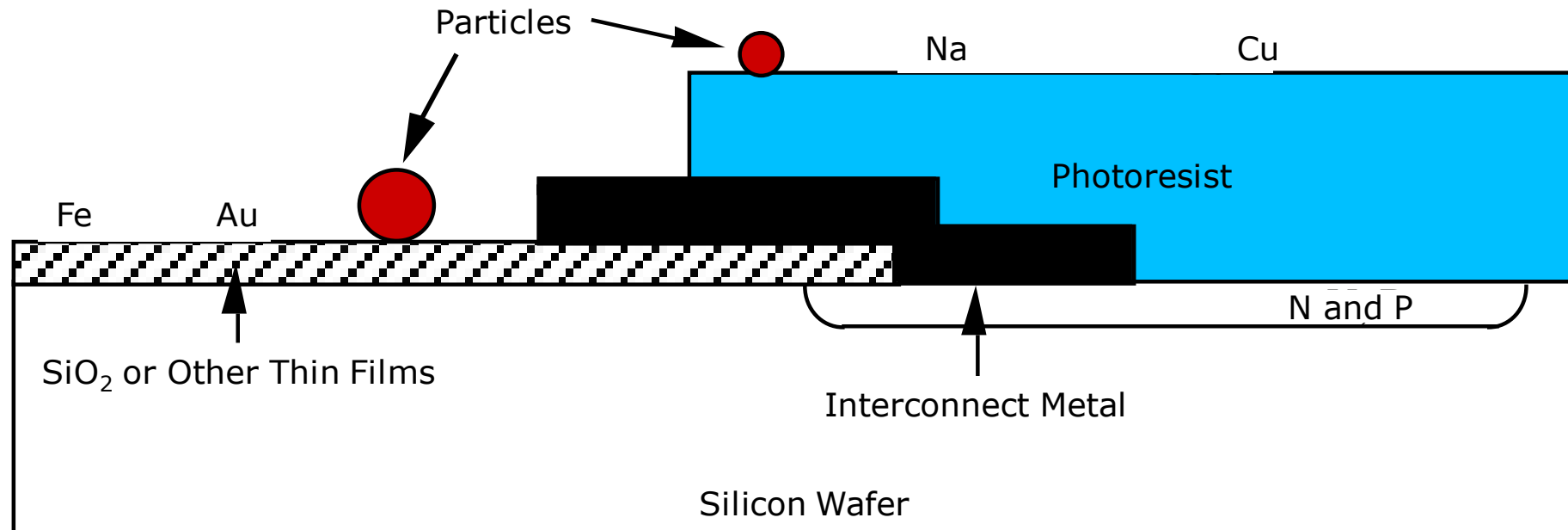
- However, the key is how to fabricate transistors with high yield and low cost.
- More importantly, even though it can be fabricated, it may not function the way we want to (quantum effect, leak current, etc.).
- Challenges lie ahead for a process engineer.
- **Hence, it is important to understand the process well.**



A clean room is required for lithography and another fabrication process as dust particles and contaminants can produce defects on the circuit pattern (pinhole, short circuit, etc.). This, in turn, decreases the yield.

Types of Contaminants in a Clean Room

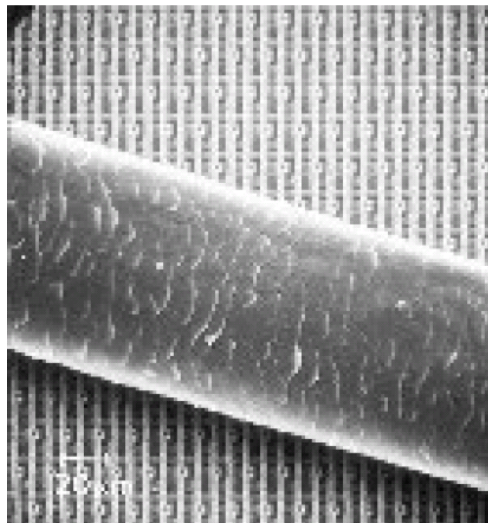
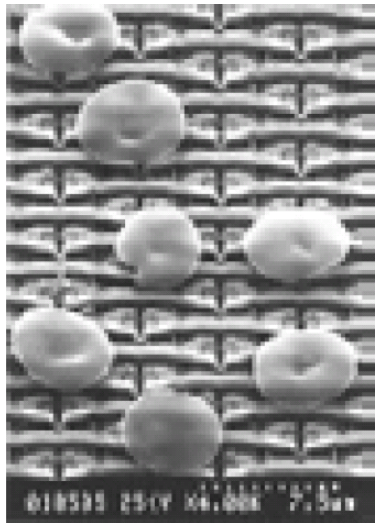
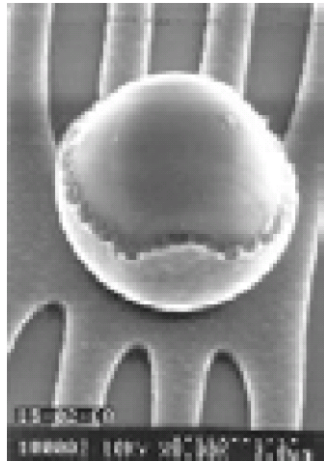
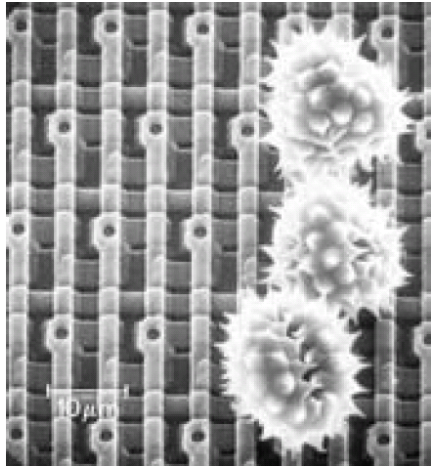
Contaminants may consist of particles, organic films, photoresist (*will be further discussed in the coming lessons*), heavy metals, or alkali ions.



Modern IC industries employ a comprehensive approach to control unwanted contaminants:

1. Clean rooms
2. Wafer cleaning

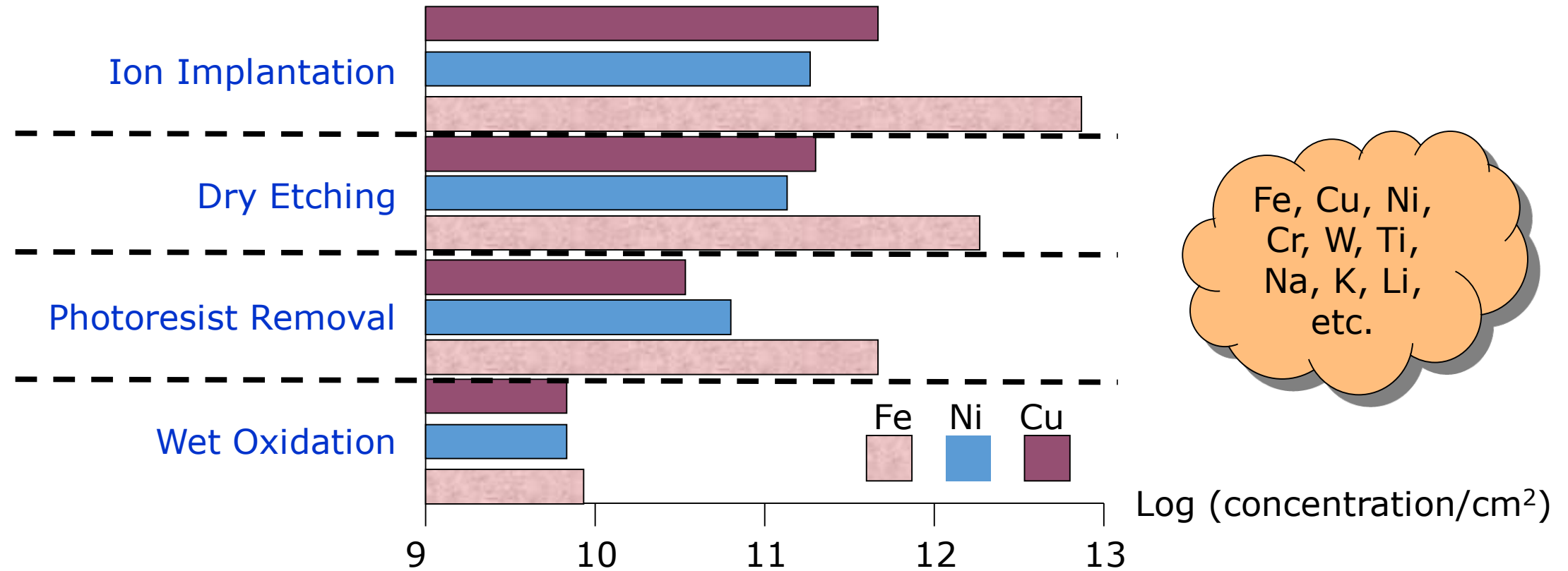
Particle Contaminants



- Particle sources: Air, people, equipment, and chemicals
- A typical person emits 5-10 million particles per minute

	> 0.2 μm	> 0.5 μm
NH ₄ OH	130-240	15-30
H ₂ O ₂	20-100	5-20
HF	0-1	0
HCl	2-7	1-2
H ₂ SO ₄	180-1,150	10-80

Particle density (number/ml) for Ultra-Large-Scale Integration (ULSI) grade chemicals



Sources: Chemicals, ion implantation, reactive ion etching, resist removal, and oxidation

Effects: Defects at interface degrade device; leads to the leak current of the p-n junction, reduces minority carrier life time

Modern IC factories employ the following approach to control unwanted impurities:

1. Clean rooms
2. Wafer cleaning



A Typical Clean Room



Wafer Cleaning

Factory environment is cleaned by:

- HEPA filters and recirculation for the air
- “Bunny suits” for workers
- Filtration of chemicals and gases
- Manufacturing protocols

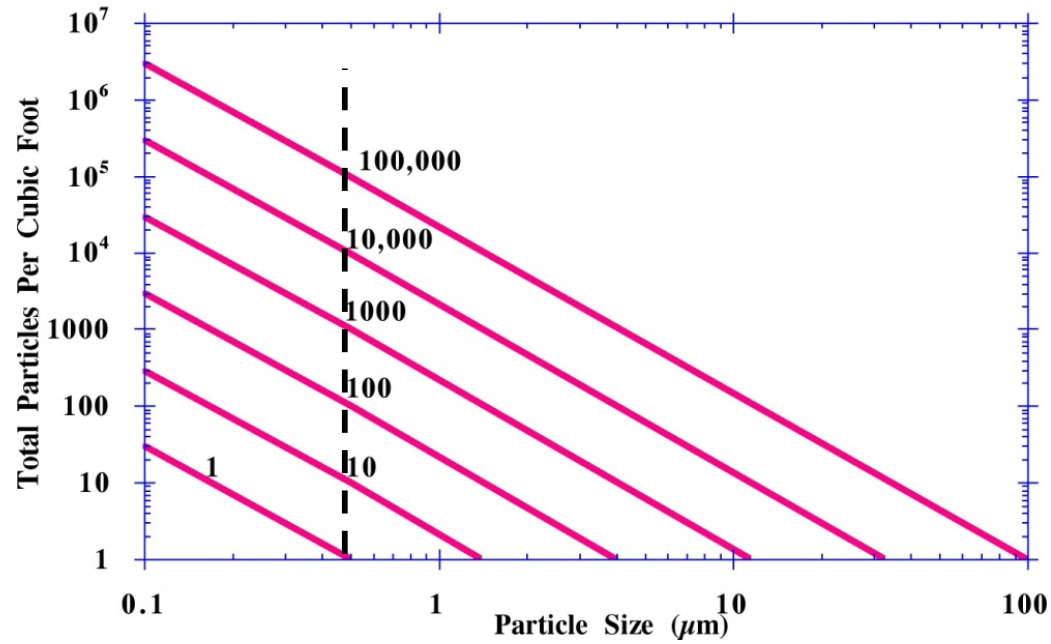


HEPA: High-Efficiency Particulate Air

- HEPA filters composed of thin porous sheets of ultrafine glass fibres ($< 1 \mu\text{m}$ diameter)
- It is 99.97% efficient at removing particles from the air
- Room air forced through the filter at 50 cm/sec
- Large particles trapped, small ones stick to the fibres due to electrostatic forces
- The exit air is typically better than class 1



Class of a Clean Room



Class	Particle diameter (μm)			
	0.1	0.3	0.5	5.0
1	35	3	1	
10	350	30	10	
100		300	100	
1,000			1,000	7
10,000			10,000	70
100,000			100,000	700

Particle count per cubic foot

- Air quality in a clean room is measured by the “class” of the facility.
- The classification is based on the number of particles count, where the diameter is greater than $0.5 \mu\text{m}$, in a cubic foot of air.
- A typical office building is about class 100,000.

- Generally, photolithography, etching, and deposition processes are needed to fabricate a semiconductor device from the silicon wafer.
- Moore's law predicted that the number of transistors on a single chip will be doubled roughly every two years by reducing the transistor feature size. Thus, understanding of photolithography, etching, and deposition processes are crucial to fabricate extremely small transistors.
- A clean room is needed to prevent contaminations (which can produce defects in the IC).